DUAL 30V N-CHANNEL ENHANCEMENT MODE MOSFET

SUMMARY

 $V_{(BR)DSS}=30V$; $R_{DS(ON)}=0.135\Omega$; $I_D=2.3A$

DESCRIPTION

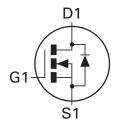
This new generation of high density MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.



FEATURES

- Low on-resistance
- · Fast switching speed
- · Low threshold
- Low gate drive
- Low profile SOIC package

G2 S2



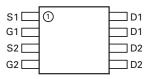
APPLICATIONS

- DC DC converters
- Power management functions
- Disconnect switches
- Motor control

Pin-out

ORDERING INFORMATION

DEVICE	REEL SIZE (inches)	TAPE WIDTH (mm)	QUANTITY PER REEL
ZXM63N03NXTA	7	12 embossed	1,000
ZXM63N03NXTC	13	12 embossed	4,000



Top view

DEVICE MARKING

ZXM63N03

ZETEX SEMICONDUCTORS

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DSS}	30	V
Gate- Source Voltage	V _{GS}	±20	V
Continuous Drain Current $ (V_{GS}{=}4.5V; T_A{=}25^{\circ}C)(b)(d) \\ (V_{GS}{=}4.5V; T_A{=}70^{\circ}C)(b)(d) $	I _D	2.3 1.8	А
Pulsed Drain Current (c)(d)	I _{DM}	14	А
Continuous Source Current (Body Diode)(b)(d)	I _S	1.5	А
Pulsed Source Current (Body Diode)(c)(d)	I _{SM}	14	А
Power Dissipation at T _A =25°C (a)(d) Linear Derating Factor	P _D	0.87 6.9	W mW/°C
Power Dissipation at T _A =25°C (a)(e) Linear Derating Factor	P _D	1.04 8.3	W mW/°C
Power Dissipation at T _A =25°C (b)(d) Linear Derating Factor	P _D	1.25 10	W mW/°C
Operating and Storage Temperature Range	T _j :T _{stg}	-55 to +150	°C

THERMAL RESISTANCE

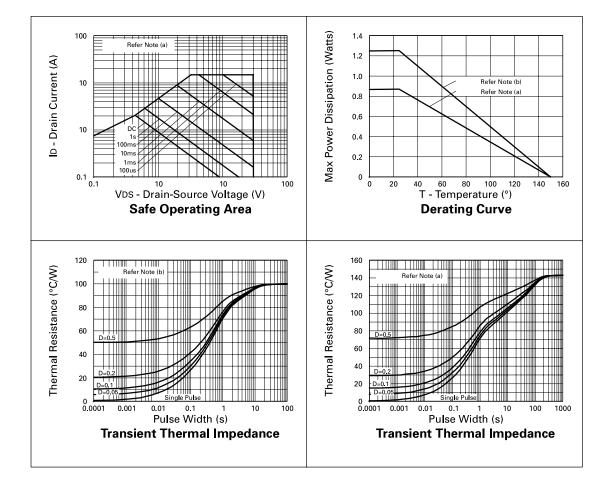
PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(d)	$R_{\theta JA}$	143	°C/W
Junction to Ambient (b)(d)	$R_{\theta JA}$	100	°C/W
Junction to Ambient (a)(e)	$R_{\theta JA}$	120	°C/W

NOTES:

- (a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions
- (c) Repetitive rating pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.
- (d) For device with one active die.
- (e) For device with two active die running at equal power.



CHARACTERISTICS



ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated)

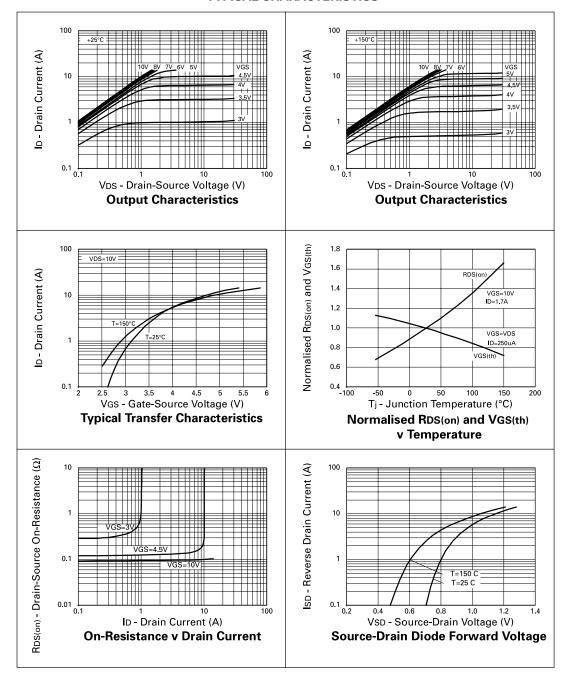
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC	'	•	•	•	•		
Drain-Source Breakdown Voltage	V _{(BR)DSS}	30			V	I _D =250μA, V _{GS} =0V	
Zero Gate Voltage Drain Current	I _{DSS}			1	μА	V _{DS} =30V, V _{GS} =0V	
Gate-Body Leakage	I _{GSS}			100	nA	V_{GS} = $\pm 20V$, V_{DS} = $0V$	
Gate-Source Threshold Voltage	V _{GS(th)}	1.0			V	I _D =250μA, V _{DS} = V _{GS}	
Static Drain-Source On-State Resistance (1)	R _{DS(on)}			0.135 0.200	Ω	V _{GS} =10V, I _D =1.7A V _{GS} =4.5V, I _D =0.85A	
Forward Transconductance (3)	g _{fs}	1.9			S	V _{DS} =10V,I _D =0.85A	
DYNAMIC (3)		•					
Input Capacitance	C _{iss}		290		pF	., .= ., ., .,	
Output Capacitance	C _{oss}		70		pF	V _{DS} =25 V, V _{GS} =0V, f=1MHz	
Reverse Transfer Capacitance	C _{rss}		20		pF]	
SWITCHING (2) (3)	•	•					
Turn-On Delay Time	t _{d(on)}		2.5		ns	V_{DD} =15V, I_{D} =1.7A R_{G} =6.1 Ω , R_{D} =8.7 Ω (Refer to test circuit)	
Rise Time	t _r		4.1		ns		
Turn-Off Delay Time	t _{d(off)}		9.6		ns		
Fall Time	t _f		4.4		ns		
Total Gate Charge	Qg			8	nC		
Gate-Source Charge	Q _{gs}			1.2	nC	V _{DS} =24V,V _{GS} =10V, I _D =1.7A	
Gate Drain Charge	Q _{gd}			2	nC	(Refer to test circuit)	
SOURCE-DRAIN DIODE		•					
Diode Forward Voltage (1)	V _{SD}			0.95	V	T _j =25°C, I _S =1.7A, V _{GS} =0V	
Reverse Recovery Time (3)	t _{rr}		16.9		ns	T _j =25°C, I _F =1.7A, di/dt= 100A/μs	
Reverse Recovery Charge(3)	Q _{rr}		9.5		nC		

NOTES

- (1) Measured under pulsed conditions. Width=300 $\mu s.$ Duty cycle @2% .
- $\hbox{(2) Switching characteristics are independent of operating junction temperature.} \\$
- (3) For design aid only, not subject to production testing.



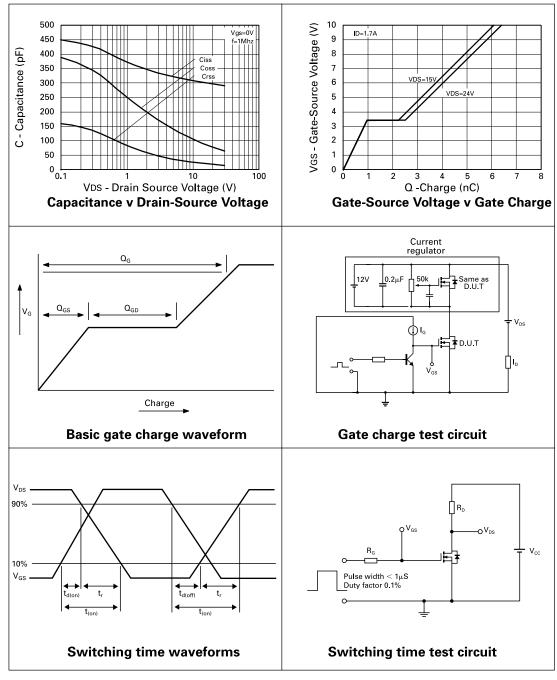
TYPICAL CHARACTERISTICS



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TYPICAL CHARACTERISTICS



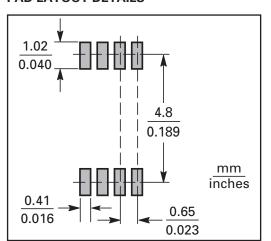
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PACKAGE DETAILS

E1

PAD LAYOUT DETAILS



PACKAGE DIMENSIONS

DIM	Millimeters		Inches		
	MIN	MAX	MIN	MAX	
Α	0.91	1.11	0.036	0.044	
A1	0.10	0.20	0.004	0.008	
В	0.25	0.36	0.010	0.014	
С	0.13	0.18	0.005	0.007	
D	2.95	3.05	0.116	0.120	
е	0.65NOM		0.0256		
e1	0.33NOM		0.0128		
Е	2.95	3.05	0.116	0.120	
Н	4.78	5.03	0.188	0.198	
L	0.41	0.66	0.016	0.026	
θ°	0°	6°	0°	6°	

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Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH	Zetex Inc	Zetex (Asia) Ltd	Zetex Semiconductors plc
Streitfeldstraße 19	700 Veterans Memorial Hwy	3701-04 Metroplaza Tower 1	Zetex Technology Park
D-81673 München	Hauppauge, NY 11788	Hing Fong Road, Kwai Fong	Chadderton, Oldham, OL9 9LL
Germany	USA	Hong Kong	United Kingdom
Telefon: (49) 89 45 49 49 0	Telephone: (1) 631 360 2222	Telephone: (852) 26100 611	Telephone (44) 161 622 4444
Fax: (49) 89 45 49 49	Fax: (1) 631 360 8222	Fax: (852) 24250 494	Fax: (44) 161 622 4446
europe.sales@zetex.com	usa.sales@zetex.com	asia.sales@zetex.com	hq@zetex.com

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